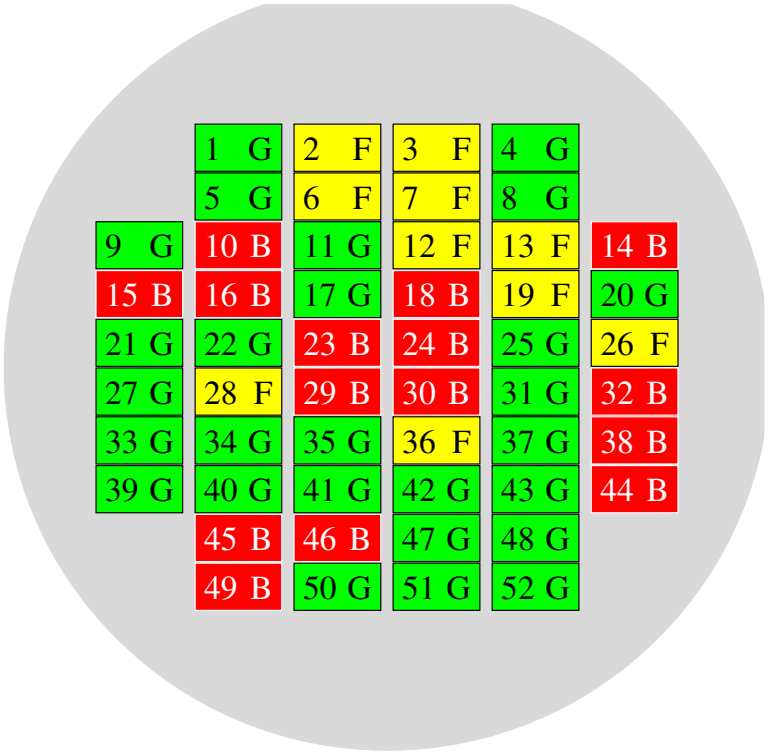
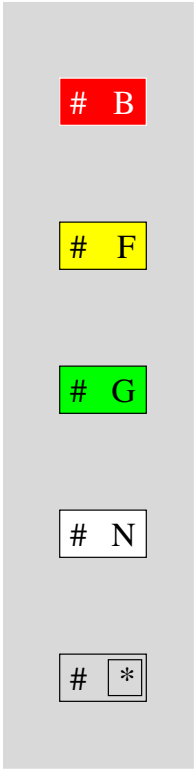
Die quality map for wafer 66 s/n: 21316-07-07

Date: 01/05/99





Bad die

Fair die

Good die

No info

Manually tagged